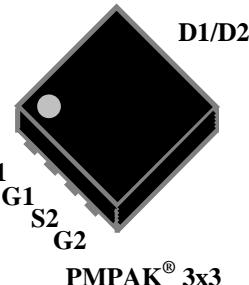




- ▼ Simple Drive Requirement
- ▼ Good Thermal Performance
- ▼ Fast Switching Performance
- ▼ RoHS Compliant & Halogen-Free

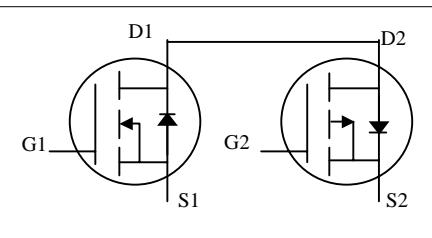


### Description

AP4537 series are from Advanced Power innovative design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

The PMPPAK® 3x3 package is special for voltage conversion application using standard infrared reflow technique with the backside heat sink to achieve the good thermal performance.

N-CH	$BV_{DSS}$	30V
	$R_{DS(ON)}$	30mΩ
	$I_D$	7.3A
P-CH	$BV_{DSS}$	-30V
	$R_{DS(ON)}$	60mΩ
	$I_D$	-5.3A



### Absolute Maximum Ratings@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Rating		Units
		N-channel	P-channel	
$V_{DS}$	Drain-Source Voltage	30	-30	V
$V_{GS}$	Gate-Source Voltage	+20	+20	V
$I_D@T_A=25^\circ\text{C}$	Drain Current <sup>3</sup> , $V_{GS} @ 10\text{V}$	7.3	-5.3	A
$I_D@T_A=70^\circ\text{C}$	Drain Current <sup>3</sup> , $V_{GS} @ 10\text{V}$	5.8	-4.2	A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	28	-20	A
$P_D@T_A=25^\circ\text{C}$	Total Power Dissipation	2.5		W
$T_{STG}$	Storage Temperature Range	-55 to 150		°C
$T_J$	Operating Junction Temperature Range	-55 to 150		°C

### Thermal Data

Symbol	Parameter	Value	Unit
$R_{thj-c}$	Maximum Thermal Resistance, Junction-case	10	°C/W
$R_{thj-a}$	Maximum Thermal Resistance, Junction-ambient <sup>3</sup>	50	°C/W


**N-CH Electrical Characteristics @  $T_j=25^\circ\text{C}$ (unless otherwise specified)**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_D=250\mu\text{A}$	30	-	-	V
$\text{R}_{\text{DS(ON)}}$	Static Drain-Source On-Resistance <sup>2</sup>	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_D=4\text{A}$	-	-	30	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_D=3\text{A}$	-	-	48	$\text{m}\Omega$
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_D=250\mu\text{A}$	1	-	3	V
$\text{g}_{\text{fs}}$	Forward Transconductance	$\text{V}_{\text{DS}}=10\text{V}, \text{I}_D=4\text{A}$	-	8.5	-	S
$\text{I}_{\text{DSS}}$	Drain-Source Leakage Current	$\text{V}_{\text{DS}}=24\text{V}, \text{V}_{\text{GS}}=0\text{V}$	-	-	10	$\mu\text{A}$
$\text{I}_{\text{GSS}}$	Gate-Source Leakage	$\text{V}_{\text{GS}}=\pm 20\text{V}, \text{V}_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
$\text{Q}_{\text{g}}$	Total Gate Charge	$\text{I}_D=4\text{A}$	-	4.5	7.2	nC
$\text{Q}_{\text{gs}}$	Gate-Source Charge	$\text{V}_{\text{DS}}=15\text{V}$	-	1	-	nC
$\text{Q}_{\text{gd}}$	Gate-Drain ("Miller") Charge	$\text{V}_{\text{GS}}=4.5\text{V}$	-	2.5	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time	$\text{V}_{\text{DS}}=15\text{V}$	-	8	-	ns
$t_{\text{r}}$	Rise Time	$\text{I}_D=1\text{A}$	-	9	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time	$\text{R}_G=3.3\Omega$	-	16	-	ns
$t_{\text{f}}$	Fall Time	$\text{V}_{\text{GS}}=10\text{V}$	-	3	-	ns
$\text{C}_{\text{iss}}$	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}$	-	250	400	pF
$\text{C}_{\text{oss}}$	Output Capacitance	$\text{V}_{\text{DS}}=25\text{V}$	-	55	-	pF
$\text{C}_{\text{rss}}$	Reverse Transfer Capacitance	f=1.0MHz	-	50	-	pF

**Source-Drain Diode**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{V}_{\text{SD}}$	Forward On Voltage <sup>2</sup>	$\text{I}_S=1.2\text{A}, \text{V}_{\text{GS}}=0\text{V}$	-	-	1.2	V
$t_{\text{rr}}$	Reverse Recovery Time	$\text{I}_S=4\text{A}, \text{V}_{\text{GS}}=0\text{V}$	-	15	-	ns
$\text{Q}_{\text{rr}}$	Reverse Recovery Charge	$d\text{I}/dt=100\text{A}/\mu\text{s}$	-	7	-	nC

**P-CH Electrical Characteristics @ $T_j=25^\circ\text{C}$ (unless otherwise specified)**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$ , $I_{\text{D}}=-250\mu\text{A}$	-30	-	-	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{\text{GS}}=-10\text{V}$ , $I_{\text{D}}=-4\text{A}$	-	-	60	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}$ , $I_{\text{D}}=-3\text{A}$	-	-	80	$\text{m}\Omega$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$ , $I_{\text{D}}=-250\mu\text{A}$	-1	-	-3	V
$g_{\text{fs}}$	Forward Transconductance	$V_{\text{DS}}=-10\text{V}$ , $I_{\text{D}}=-4\text{A}$	-	9	-	S
$I_{\text{DSS}}$	Drain-Source Leakage Current	$V_{\text{DS}}=-24\text{V}$ , $V_{\text{GS}}=0\text{V}$	-	-	-10	$\text{uA}$
$I_{\text{GSS}}$	Gate-Source Leakage	$V_{\text{GS}}=\pm 20\text{V}$ , $V_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
$Q_{\text{g}}$	Total Gate Charge	$I_{\text{D}}=-4\text{A}$	-	7	11.2	nC
$Q_{\text{gs}}$	Gate-Source Charge	$V_{\text{DS}}=-15\text{V}$	-	1.5	-	nC
$Q_{\text{gd}}$	Gate-Drain ("Miller") Charge	$V_{\text{GS}}=-4.5\text{V}$	-	3.5	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time	$V_{\text{DS}}=-15\text{V}$	-	10	-	ns
$t_{\text{r}}$	Rise Time	$I_{\text{D}}=-1\text{A}$	-	11	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time	$R_{\text{G}}=3.3\Omega$	-	22	-	ns
$t_{\text{f}}$	Fall Time	$V_{\text{GS}}=-10\text{V}$	-	9	-	ns
$C_{\text{iss}}$	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	570	910	pF
$C_{\text{oss}}$	Output Capacitance	$V_{\text{DS}}=-25\text{V}$	-	80	-	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance	f=1.0MHz	-	75	-	pF

**Source-Drain Diode**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$V_{\text{SD}}$	Forward On Voltage <sup>2</sup>	$I_{\text{S}}=-1.2\text{A}$ , $V_{\text{GS}}=0\text{V}$	-	-	-1.2	V
$t_{\text{rr}}$	Reverse Recovery Time	$I_{\text{S}}=-4\text{A}$ , $V_{\text{GS}}=0\text{V}$	-	19	-	ns
			-	13	-	nC

**Notes:**

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board, t  $\leq$  10sec, 90°C/W at steady state.

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

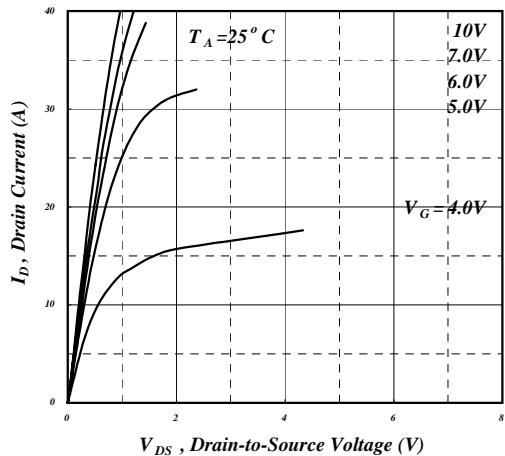
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APEC RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN.

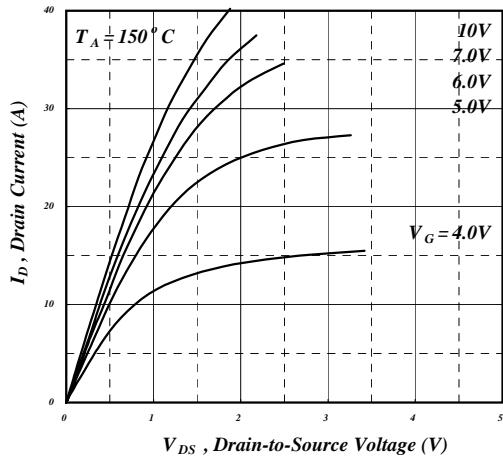
# AP4537GYT-HF



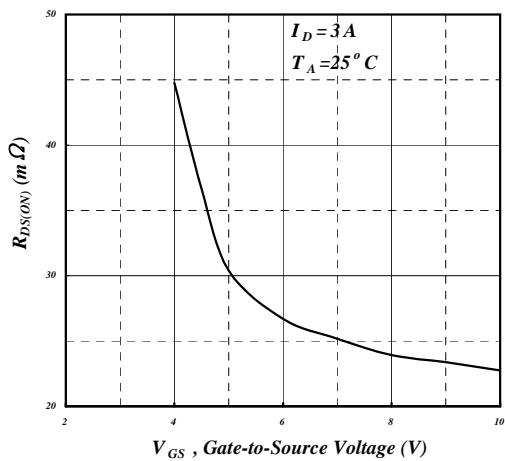
## N-Channel



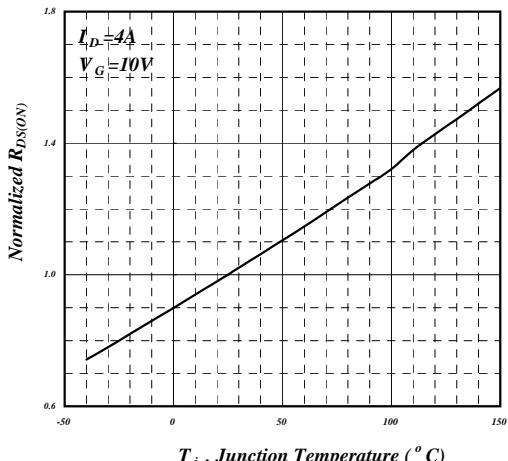
**Fig 1. Typical Output Characteristics**



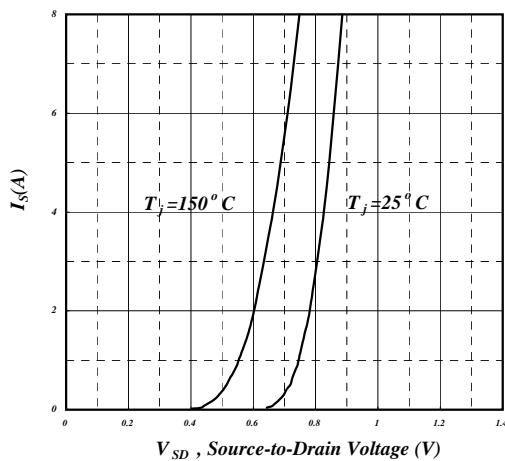
**Fig 2. Typical Output Characteristics**



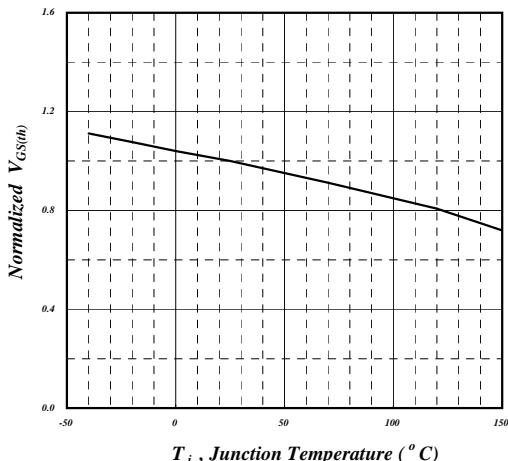
**Fig 3. On-Resistance v.s. Gate Voltage**



**Fig 4. Normalized On-Resistance v.s. Junction Temperature**



**Fig 5. Forward Characteristic of Reverse Diode**



**Fig 6. Gate Threshold Voltage v.s. Junction Temperature**



## N-Channel

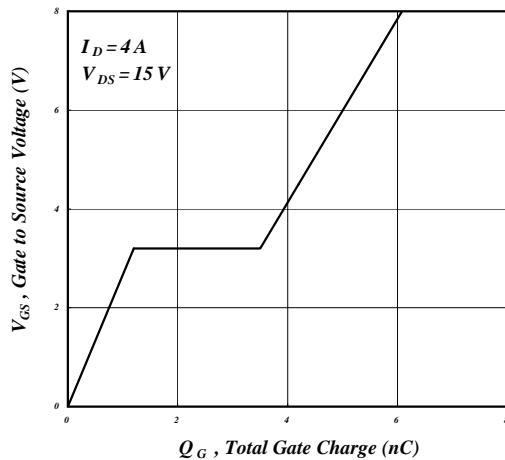


Fig 7. Gate Charge Characteristics

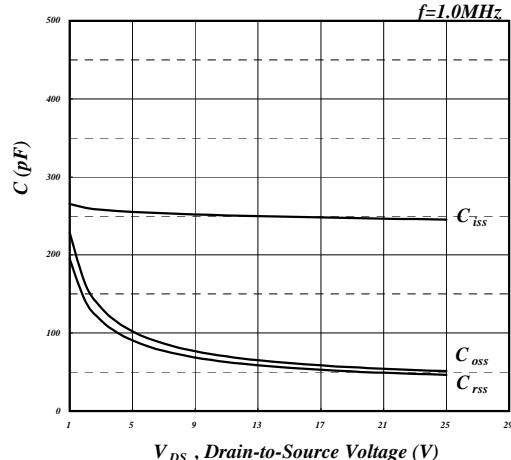


Fig 8. Typical Capacitance Characteristics

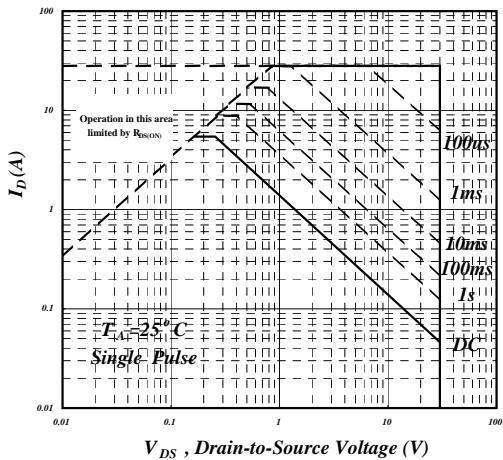


Fig 9. Maximum Safe Operating Area

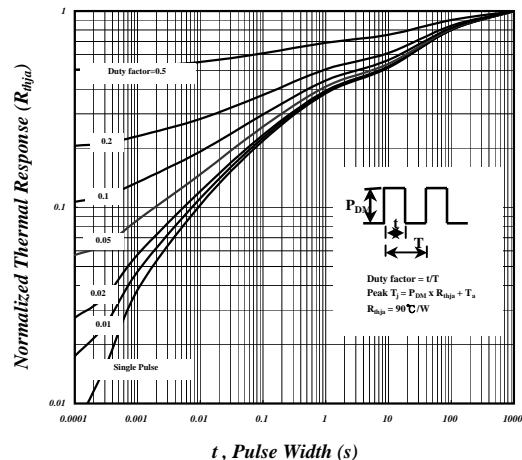


Fig 10. Effective Transient Thermal Impedance

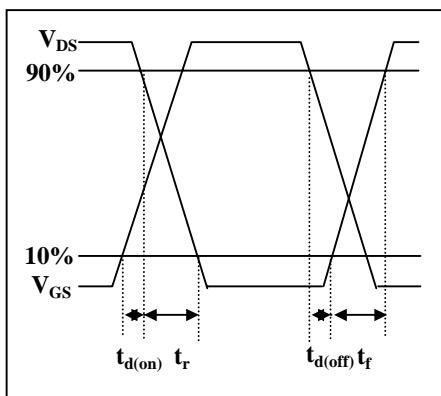


Fig 11. Switching Time Waveform

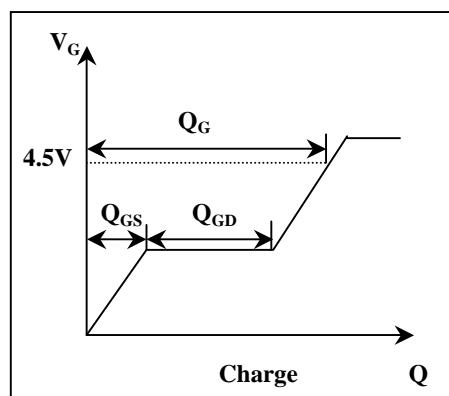
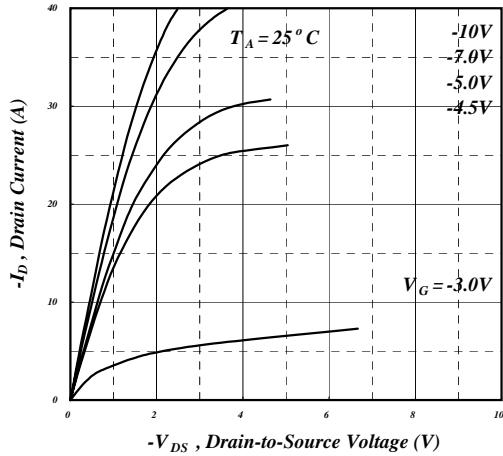


Fig 12. Gate Charge Waveform

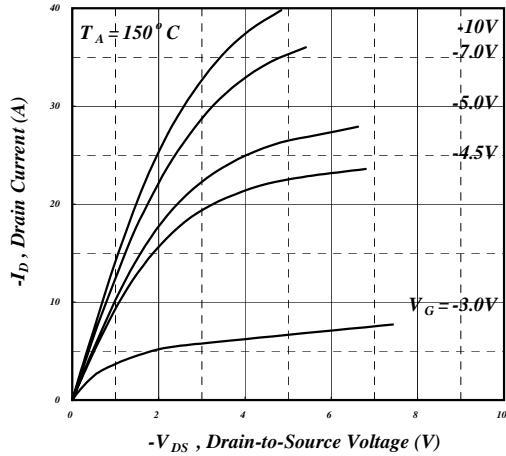
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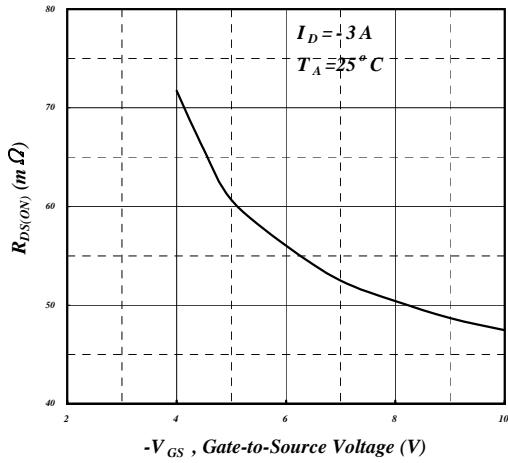
## P-Channel



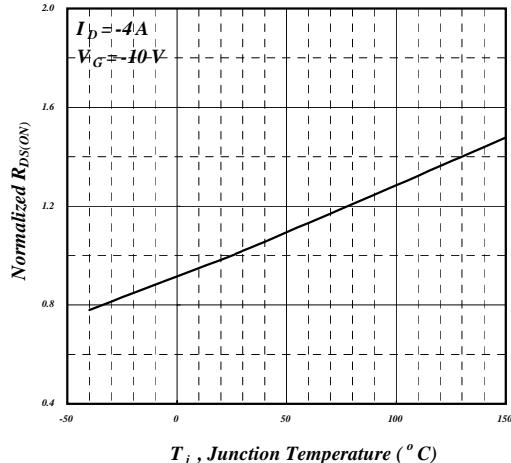
**Fig 1. Typical Output Characteristics**



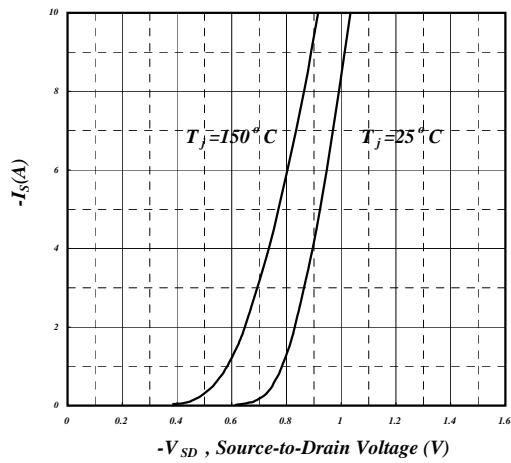
**Fig 2. Typical Output Characteristics**



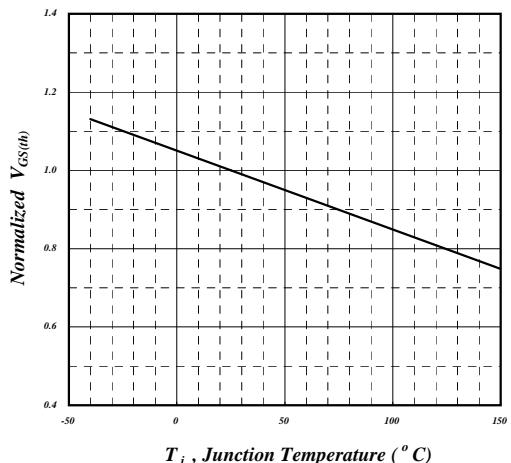
**Fig 3. On-Resistance v.s. Gate Voltage**



**Fig 4. Normalized On-Resistance v.s. Junction Temperature**



**Fig 5. Forward Characteristic of Reverse Diode**



**Fig 6. Gate Threshold Voltage v.s. Junction Temperature**



## P-Channel

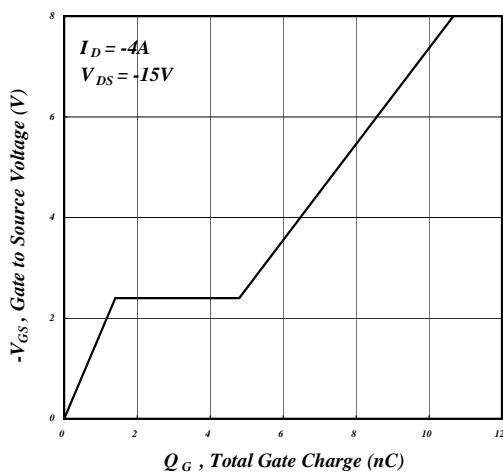


Fig 7. Gate Charge Characteristics

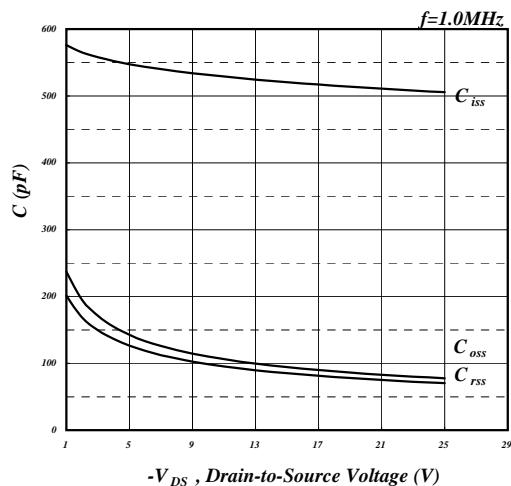


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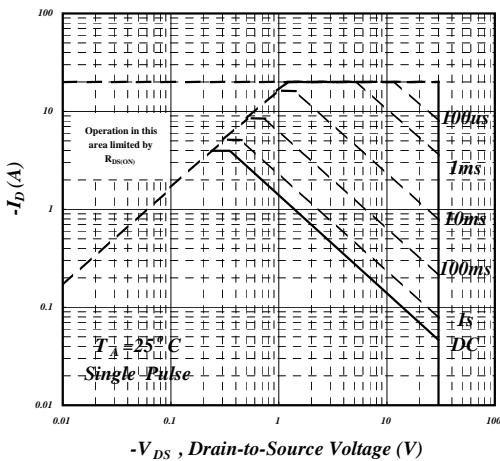


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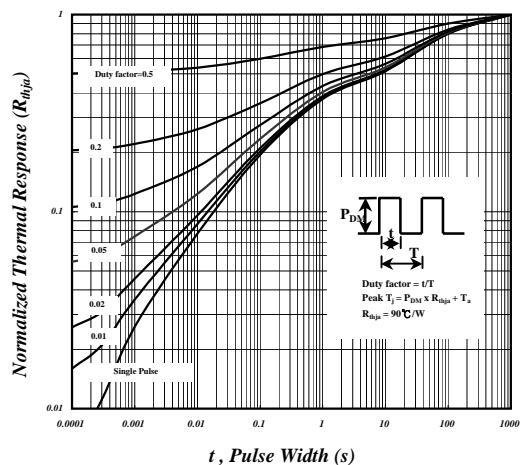


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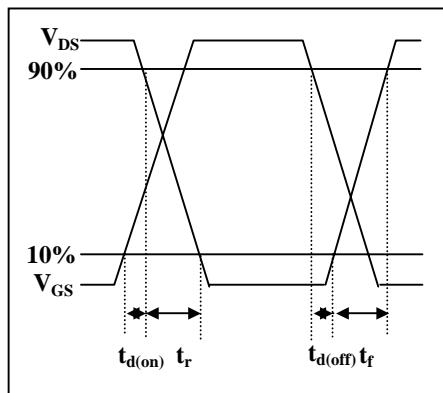


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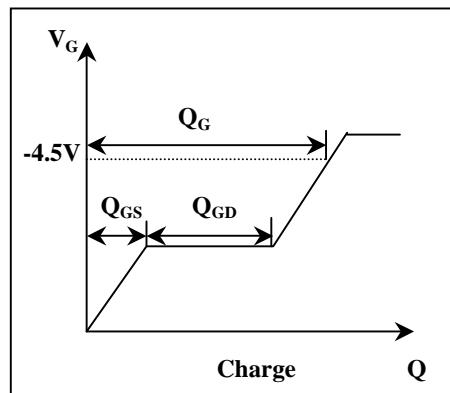


Fig 12. Gate Charge Waveform



**AP4537GYT-HF**

## **MARKING INFORMATION**

